

23. (New) The method of claim 19, further comprising providing an oscillating control signal to the pass circuit.
24. (New) The method of claim 23, further comprising using a ring oscillator to provide the oscillating control signal to the pass circuit.
25. (New) The method of claim 19, further comprising using a pass control circuit to apply a desired voltage to the internal node, thereby forcing the voltage at the internal node to the desired voltage.
26. (New) The method of claim 19, wherein the pass circuit comprises:
a pass gate having first, second, and third terminals, the first terminal coupled to a pass control circuit, the second terminal coupled to the internal node, the third terminal coupled to the pin; and
a capacitor coupled between the first terminal of the pass gate and the pass control circuit such that a voltage at the first terminal of the pass gate is driven to cause a voltage at the second terminal voltage to be passed to the third terminal for reading the voltage at the internal node.
27. (New) The method of claim 26, wherein the pass gate comprises an n-channel MOS transistor.
28. (New) A method for forcing a voltage at an internal node of an integrated circuit to a desired level, the method comprising:
coupling a pass circuit between the internal node and a pin of the integrated circuit;
applying a voltage of the desired level to the pin;
using a reset circuit to activate the pass circuit; and
driving the pass circuit to pass the applied voltage from the pin to the internal node, thereby forcing the voltage at the internal node to the desired level.

29. (New) The method of claim 28, further comprising using a pass control circuit to drive the pass circuit.

30. (New) The method of claim 28, wherein the pass control circuit comprises an n-channel MOS transistor having a drain coupled to the internal node, the n-channel MOS transistor configured to, when turned on, pass the voltage at the internal node to a source of the n-channel MOS transistor and to the pass circuit.

31. (New) The method of claim 28, further comprising providing an oscillating control signal to the pass circuit.

32. (New) The method of claim 31, further comprising using a ring oscillator to provide the oscillating control signal to the pass circuit.

33. (New) The method of claim 28, wherein the pass circuit comprises:

a pass gate having first, second, and third terminals, the first terminal coupled to a pass control circuit, the second terminal coupled to the internal node, the third terminal coupled to the pin; and

a capacitor coupled between the first terminal of the pass gate and the pass control circuit such that a voltage at the first terminal of the pass gate is driven to cause a voltage at the second terminal voltage to be passed to the third terminal for reading the voltage at the internal node.

SUPPLEMENTAL PRELIMINARY AMENDMENT

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34. (New) The method of claim 33, wherein the pass gate comprises an n-channel MOS transistor.

The Examiner is invited to contact the below-signed attorney to discuss any questions which may remain with respect to the present application.

Respectfully submitted,

DANIEL R. LOUGHMILLER ET AL.

By their Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
P.O. Box 2938
Minneapolis, MN 55402
(612) 373-6919

Date December 19, 2000 By [Signature]
Allen J. Oh
Reg. No. 42,047

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner of Patents, Washington, D.C. 20231, on this 19th day of December, 2000.

Name Allen J. Oh

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